

LCK4310 Low-Voltage PLL Clock Driver

1 Features

- Output operating frequencies up to 1.25 GHz max.
- 100 ps part-to-part skew.
- 40 ps typical output-to-output skew.
- Cycle-to-cycle jitter 5 ps max.
- 3.3 V and 2.5 V compatible.
- Internal input pulldown resistors.
- Q output will default low with inputs open or at VEE.
- Meets or exceeds Joint Electron Device Engineering Council (JEDEC) specification EIA®/JESD78 IC latchup test.
- Moisture sensitivity level 1.
- Flammability rating: *UL*®–94 code V–0 at 1/8 in., oxygen index 28 to 34.
- Pin-for-pin compatible with *ON Semiconductor*® part number MC100LVE310.

2 Description

The LCK4310 is a low-voltage, low-skew 2:8 differential emitter-coupled logic (ECL) fanout buffer designed with clock distribution in mind. The device features fully differential clock paths to minimize both device and system skew. The LCK4310 offers two selectable clock inputs to allow for redundant or test clocks to be incorporated into the system clock trees.

To ensure that the tight skew specification is met, it is necessary that both sides of the differential output are terminated into $50~\Omega$, even if only one side is being used. In most applications, all eight differential pairs will be used and therefore terminated. In the case where fewer than eight pairs are used and in order to maintain minimum skew, it is necessary to terminate at least the output pairs adjacent to the output pair being used. Failure to follow this guideline will result in small degradations of propagation delay (on the order of 10 ps—20 ps) of the outputs being used. While not catastrophic to most designs, this will result in an increase in skew.

Note: The package corners isolate outputs from one another such that the guideline expressed above holds only for outputs on the same side of the package.

The LCK4310, as with most ECL devices, can be operated from a positive voltage supply (VDD) in LVPECL mode. This allows the LCK4310 to be used for high-performance clock distribution in 3.3 V/2.5 V systems. Designers can take advantage of the LCK4310's performance to distribute low-skew clocks across the backplane or the board. In a PECL environment (series or Thevenin), line terminations are typically used since they require no additional power supplies. If parallel termination is desired, a terminating voltage of VDD – 2.0 V will need to be provided.

An internally generated voltage supply (VBB pin) is available to this device only. For single-ended input conditions, the unused differential input is connected to VBB as a switching reference voltage. VBB may also rebias ac coupled inputs. When used, decouple VBB and VDD via a 0.01 μF capacitor and limit current sourcing or sinking to 0.5 mA. When not used, VBB should be left open.

3 Pin Information

3.1 Pin Diagram

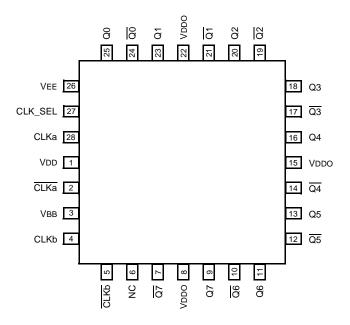


Figure 3-1. 28-Pin PLCC

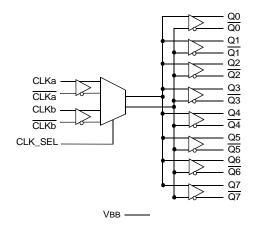
WARNING: All VDD, VDDO, and VEE pins must be externally connected to a power supply to guarantee proper operation.

3.2 Pin Descriptions

Table 3-1. Pin Descriptions

Pin	Symbol	Туре	1/0	Description
1	Vdd	Power	_	Positive Power Supply.
2	CLKa	PECL	I	ECL Differential Input Clock. Makes input pair with CLKa.
3	Vвв	VREFOUT	0	Reference Voltage Output.
4	CLKb	PECL	I	ECL Differential Input Clock. Makes input pair with CLKb.
5	CLKb	PECL	I	ECL Differential Input Clock. Makes input pair with CLKb.
6	NC	_	_	No Connect.
7, 10, 12, 14, 17, 19, 21, 24	Q[7:0]	PECL	0	ECL Differential Outputs.
8, 15, 22	Vddo	Power	_	Positive Power Supply.
9, 11, 13, 16, 18, 20, 23, 25	Q[7:0]	PECL	0	ECL Differential Outputs.
26	VEE	Power	_	Negative Power Supply.
27	CLK_SEL	LVTTL	Ι	ECL Input Clock Select.
				0 = CLKa selected.
				1 = CLKb selected.
28	CLKa	PECL	I	ECL Differential Input Clock. Makes input pair with CLKa.

3.3 Logic Symbol



CLK_SEL	Input Clock			
L	CLKa/CLKa Selected			
Н	CLKb/CLKb Selected			

Figure 3-2. Logic Symbol

4 Absolute Maximum Ratings

Stresses which exceed the absolute maximum ratings can cause permanent damage to the device. These are absolute stress ratings only. Functional operation of the device is not implied at these or any other conditions in excess of those given in the operational sections of the data sheet. Exposure to absolute maximum ratings for extended periods of time can adversely affect device reliability.

Table 4-1. Absolute Maximum Ratings

Parameter	Symbol	Conditions	Min	Max	Unit
PECL Mode Positive Power Supply	Vdd	VEE = 0 V	0	5	V
Input Voltage: PECL Mode Positive Input Voltage	Vı	VEE = 0 V, VI ≤ VDD	0	5	V
Output Current	lout	Continuous surge	50	100	mA
VBB Sink/Source	Івв	_	-0.5	0.5	mA
Storage Temperature Range	Tstg	_	-65	150	°C
Wave Solder	Tsol	<2 s to 3 s at 248 °C	_	265	°C

4.1 Handling Precautions

Although electrostatic discharge (ESD) protection circuitry has been designed into this device, proper precautions must be taken to avoid exposure to ESD and electrical overstress (EOS) during all handling, assembly, and test operations. Agere employs both a human-body model (HBM) and a charged-device model (CDM) qualification requirement in order to determine ESD-susceptibility limits and protection design evaluation. ESD voltage thresholds are dependent on the circuit parameters used in each of the models, as defined by JEDEC's JESD22-A114 (HBM) and JESD22-C101 (CDM) standards.

Table 4-2. ESD Tolerance

Device	Minimum Thresho	ld
	НВМ	CDM
LCK4310	>2,000 V	>1,000 V

4.2 Thermal Parameters (Definitions and Values)

System and circuit board level performance depends not only on device electrical characteristics, but also on device thermal characteristics. The thermal characteristics frequently determine the limits of circuit board or system performance, and they can be a major cost adder or cost avoidance factor. When the die temperature is kept below 125 °C, temperature activated failure mechanisms are minimized. The thermal parameters that Agere provides for its packages help the chip and system designer choose the best package for their applications, including allowing the system designer to thermally design and integrate their systems.

It should be noted that all the parameters listed below are affected, to varying degrees, by package design (including paddle size) and choice of materials, the amount of copper in the test board or system board, and system airflow.

ΘJA - Junction to Air Thermal Resistance

ΘJA is a number used to express the thermal performance of a part under JEDEC standard natural convection conditions. ΘJA is calculated using the following formula:

$$\Theta$$
JA = (TJ - Tamb) / P; where P = power

ОJMA - Junction to Moving Air Thermal Resistance

ΘJMA is effectively identical to ΘJA but represents performance of a part mounted on a JEDEC four layer board inside a wind tunnel with forced air convection. ΘJMA is reported at airflows of 200 LFPM and 500 LFPM (linear feet per minute), which roughly correspond to 1 m/s and 2.5 m/s (respectively). ΘJMA is calculated using the following formula:

$$\Theta$$
JMA = (TJ - Tamb) / P

⊙JC - Junction to Case Thermal Resistance

ΘJC is the thermal resistance from junction to the top of the case. This number is determined by forcing nearly 100% of the heat generated in the die out the top of the package by lowering the top case temperature. This is done by placing the top of the package in contact with a copper slug kept at room temperature using a liquid refrigeration unit. ΘJC is calculated using the following formula:

$$\Theta JC = (TJ - TC) / P$$

Table 4-3. Thermal Parameter Values

Parameter	Temperature °C/Watt
ΘЈΑ	63.5
ΘJMA (500 lf/m)	43.5
Θις	27.3

5 Electrical Characteristics

5.1 dc Characteristics

Table 5-1. LVPECL 3.3 V dc Characteristics

VDD = 3.3 V, VEE = 0 V. Input and output parameters vary 1:1 with VDD. VEE can vary $\pm 0.3 \text{ V}$. Devices are designed to meet the dc specifications shown in this table, after thermal equilibrium has been established.

Parameter	Symbol	−40 °C		25 °C			85 °C			Unit	
		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
Power Supply Current	lee	_	55	60	_	55	60	_	65	70	mA
Output High Voltage*	Voн	2.215	2.295	2.420	2.275	2.345	2.420	2.275	2.345	2.420	V
Output Low Voltage*	Vol	1.470	1.605	1.745	1.490	1.595	1.680	1.490	1.595	1.680	V
Input High Voltage (sin- gle-ended)	VIH	2.135	_	2.420	2.135	_	2.420	2.135	_	2.420	V
Input Low Voltage (sin- gle-ended)	VIL	1.490	_	1.825	1.490	_	1.825	1.490	_	1.825	V
Output Voltage Reference	Vвв	1.92	_	2.06	1.92	_	2.06	1.92	_	2.06	V
Input High Voltage Common-mode Range (differential) [†]	VIHCMR	1.8	_	2.9	1.8	_	2.9	1.8	_	2.9	V
Input High Current	lін	_	_	150	_	_	150	_	_	150	μA
Input Low Current	lıL	0.5	_	_	0.5			0.5		_	μΑ

^{*} Outputs are terminated through a 50 Ω resistor to VDD – 2 V.

[†] VIHCMR minimum varies 1:1 with VEE, maximum varies 1:1 with VDD. VIHCMR is defined as the range within which the VIH level may vary, with the device still meeting the propagation delay specification. The VIL level must be such that the peak-to-peak voltage is less than 1.0 V and greater than or equal to Vp-pmin.

Table 5-2. LVPECL 2.5 V dc Characteristics

VDD = 2.5 V, VEE = 0 V. Input and output parameters vary 1:1 with VDD. VEE can vary $\pm 0.3 \text{ V}$. Devices are designed to meet the dc specifications shown in this table, after thermal equilibrium has been established.

Parameter	Symbol	−40 °C		25 °C			85 °C			Unit	
		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
Power Supply Current	IEE	_	55	60	_	55	60	_	65	70	mA
Output High Voltage*	Voн	1.425	1.495	1.620	1.425	1.507	1.620	1.425	1.520	1.620	V
Output Low Voltage*	Vol	0.730	0.790	0.955	0.730	0.820	0.955	0.730	0.825	0.955	V
Input High Voltage (single-ended)	ViH	2.000	_	2.400	2.000	_	2.400	2.000	_	2.400	V
Input Low Voltage (single-ended)	VIL	0.400	_	1.030	0.400	_	1.030	0.400	_	1.030	V
Output Voltage Reference	Vвв	1.019	_	1.361	1.019	_	1.361	1.019	_	1.361	V
Input High Voltage Common-mode Range (differential) [†]	VIHCMR	1.0	_	2.1	1.0	_	2.1	1.0	_	2.1	V
Input High Current	lін	_	_	150	_	_	150	_	_	150	μA
Input Low Current	lıL	0.5			0.5		_	0.5	_		μA

 $^{^*}$ Outputs are terminated through a 50 Ω resistor to VDD – 2 V.

[†] VIHCMR minimum varies 1:1 with VEE, maximum varies 1:1 with VDD. VIHCMR is defined as the range within which the VIH level may vary, with the device still meeting the propagation delay specification. The VIL level must be such that the peak-to-peak voltage is less than 1.0 V and greater than or equal to Vp-pmin.

5.2 ac Characteristics

VDD = 3.3/2.5 V, VEE = 0 V, or VDD = 0 V, VEE = -3.3/2.5 V. $VEE can vary <math>\pm 0.3 \text{ V}$.

Table 5-3. ac Characteristics

Parameter	Symbol		−40 °C			25 °C			85 °C		Unit
		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
Maximum Toggle Frequency	fMAX	_	_	1.25	_	_	1.25	_	_	1.25	GHz
Propagation Delay to Output: In (differential)* In (single-ended)†	tPLH tPHL	525 500		725 750	550 550	_	750 800	575 600	_	775 850	ps
Within Device Skew [‡]	tskew	_	_	40	_		40	_	_	40	ps
Part-to-part Skew [‡] (differential)	tskew	_		100	_	_	100	_	_	100	ps
Jitter	JITcyc-cyc	_	_	5	_	_	5	_	_	5	ps
	JIT _{p-p}	_	_	7	_	_	7	_	_	7	
Input Swing§	Vp-p	0.500	_	1	0.500	_	1	0.500	_	1	V
Output Rise/Fall Time (20%—80%)	tr/tf	200	_	600	200	_	600	200	_	600	ps

^{*} The differential propagation delay is defined as the delay from the crossing points of the differential input signals to the crossing point of the differential output signals.

[§] Vp-pmin is defined as the minimum input differential voltage which will cause no increase in the propagation delay. The Vp-pmin is ac limited for the LCK4310 as a differential input as low as 50 mV will still produce full ECL levels at the output.

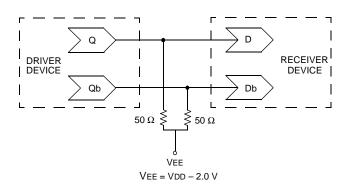


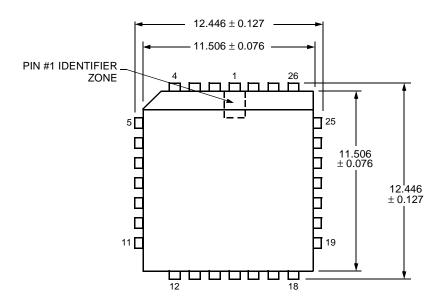
Figure 5-1. Typical Termination for Output Driver and Device Evaluation

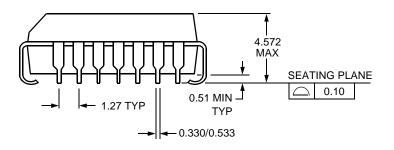
[†] The single-ended propagation delay is defined as the delay from the 50% point of the input signal to the 50% point of the output signal.

[‡] The within device skew is defined as the worst case difference between any two similar delay paths within a single device.

6 Outline Diagrams

Dimensions are in millimeters.





5-2608 (F)

7 Ordering Information

Table 7-1. Ordering Information

Device	Part Number	Pin Count	Package	Туре	Comcode
LCK4310	LCK4310GF-DB	28	PLCC	Reel	700020216
	LCK4310GF-DT	28	PLCC	Tape	700020217

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